Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/512,066	MATSUURA ET AL.	
Examiner	Art Unit	
Rip A. Lee	1713	

-	SEAR	RCHED	
Class	Subclass	Date	Examiner
526	336	06/29/20	061
526	340.2		
526	3403		
524	348		
326	74 8 73	1	

INI	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
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	SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
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